Dictionary name: cif_pd.dic Dictionary version: 0.99 Dictionary last updated: 1997-01-30

_pd_block_[pd]

_pd_block_id is used to assign a unique id code to a data block. This code is then used for references between different blocks (see _pd_block_diffractogram_id, _pd_calib_std_external_id and _pd_phase_block_id).

Note that a data block may contain only a single diffraction dataset or information about a single crystalline phase. Yet a single diffraction measurement may yield structural information on more than one phase, or a single structural determination may use more than one dataset. Alternatively, results from a single dataset, such as calibration parameters from measurements of a standard, may be used for many subsequent analyses. Through use of the id code, a reference made between datasets may be preserved when the file is exported from the laboratory where the CIF originated.

The id code assigned to each data block should be unique with respect to id code assigned for any other data block in the world. The naming scheme chosen for the block-id format is designed to ensure uniqueness.

It is the responsibility of a data archive site or local laboratory to create a catalogue of block id's, if that site wishes to resolve these references.

_pd_block_id

(char)

Used to assign a unique character string to a block. Note that this code is not intended to be parsed; the concatenation of several strings is used in order to generate a string that can reasonably be expected to be unique.

This code is assigned by the originator of the dataset and is used for references between different CIF blocks. The id will normally be created when the block is first created. It is possible to loop more than one id for a block: if changes or additions are later made to the block, a new id may be assigned, but the original name should be retained.

The format for the id code is:

<date-time> |<block_name> |<creator_name> |<instr._name>

<date-time> is the date and time the CIF was created or modified.

<block_name> is an arbitrary name assigned by the originator of the dataset. It will usually match the name of the phase and possibly the data_ name. It may be a sample name.

<creator_name> is the name of the person who measured the diffractogram, prepared or modified the CIF.

<instr._name> is a unique name [so far as possible] for the data collection instrument, preferably containing the instrument serial number for commercial instruments. It is also possible to use the Internet name or address for the instrument computer as a unique name.

As blocks are created in a CIF, the original <sample_id> should be retained, but the <creator_name> may be changed and the <date-time> will always change. The <date-time> will usually match either the _pd_meas_datetime_initiated or the _pd_proc_info_datetime entry.

Within each section of the code, the following characters may be used:

The sections are separated with vertical bars '|' which are not allowed within the sections. Blank spaces may also not be used. Capitalization be may used within the id code but should not be considered significant - searches for dataset id names should be case insensitive.

Date-time entries are in the standard CIF format 'yyyy-mmddThh:mm:ss+zz' Use of seconds and a time zone is optional, but use of hours and minutes is strongly encouraged as this will help ensure that id code is unique.

An archive site that wishes to make CIF files available via WWW may substitute the URL for the file containing the appropriate block for the final two sections of the id (<creator_name> and <instr._name>.) Note that this should not be done unless the archive site is prepared to keep the file available on-line indefinitely.

May appear in list.

Example(s):

'1991-15-09T16:54|Si-std|B. Toby|D500#1234-987',

'1991-15-09T16:54 SEPD7234 B. Toby SEPD. IPNS. ANL. GOV' [pd block]

_pd_block_diffractogram_id

(char)

A block id code (see _pd_block_id) that identifies diffraction data contained in a data block other than the current block. This will most frequently occur when more than one set of diffraction data is used for a structural determination. The data block containing the diffraction data will contain a _pd_block_id code matching the code in _pd_block_diffractogram_id. Appears in list.

[pd_proc]

_pd_meas_[pd]

This section contains the measured diffractogram and information about conditions used for measurement of the diffraction dataset, prior to processing and application of correction terms. While additional information may be added to the CIF as data are processed and transported between laboratories (possibly with addition of a new _pd_block_id entry), the information in this section of the CIF will rarely be changed once data collection is complete.

Where possible, measurements in this section should have no post-collection processing applied (normalizations, corrections, smoothing, zero-offset corrections, etc.). Such corrected measurements should be recorded in the _pd_proc_ section.

Datasets that are measured as counts, where the estimated standard deviations (e.s.d.'s) are the square-root of the intensity, should be recorded in the _pd_meas_counts_* fields. All other intensity values should be recorded using _pd_meas_intensity_*.

Example 1

Example 1	
_pd_meas_info_author_name	'Lachlan Cranswick'
_pd_meas_info_author_email	lachlan@dmp.csiro.au
_pd_meas_info_author_address	?
_pd_meas_datetime_initiated	1992-03-23T17:20
_pd_meas_scan_method	step
_pd_meas_2theta_range_min	6.0
_pd_meas_2theta_range_max	164.0
_pd_meas_2theta_range_inc	0.025
_pd_meas_step_count_time	2.0

_pd_meas_info_author_address (char)

The address of the person who measured the dataset. If there is more than one person they will be looped with _pd_meas_info_author_name.

May appear in list containing _pd_meas_info_author_name. [pd_meas_info]

_pd_meas_info_author_email (char)

The email address of the person who measured the dataset. If there is more than one person they will be looped with _pd_meas_info_author_name.

May appear in list containing _pd_meas_info_author_name. [pd meas info]

_pd_meas_info_author_fax (char)

The fax number of the person who measured the dataset. If there is more than one person they will be looped with _pd_meas_info_author_name.

May appear in list containing _pd_meas_info_author_name. [pd_meas_info]

_pd_meas_info_author_name (char)

The name of the person who measured the dataset. The family name(s), followed by a comma, precedes the first names or initials. For more than one person use a loop to specify multiple values.

May appear in list. [pd_meas_info]

_pd_meas_info_author_phone (char)

The telephone number of the person who measured the dataset. If there is more than one person they will be looped with _pd_meas_info_author_name.

May appear in list containing _pd_meas_info_author_name. [pd_meas_info]

_pd_meas_number_of_points (numb)

The total number of points in the measured diffractogram.

The permitted range is $1 \rightarrow \infty$. [pd_meas_method]

_pd_meas_datetime_initiated (char)

The date and time of the dataset measurement. Entries follow the standard CIF format 'yyyy-mm-ddThh:mm:ss+zz'. Use of seconds and a time zone is optional, but use of hours and minutes is strongly encouraged. Where possible give the time when the measurement was started rather than when completed.

	Example(s):	'1990-07-13T14:40'	[pd_meas_method]
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_pd_meas_special_details (char) Special details of the diffraction measurement process. Include information about source instability, degradation, etc. However, this item should not be used to record information that can be specified in other _pd_meas_* entries.

[pd_meas_method]

_pd_meas_counts_total _pd_meas_counts_background

```
_pd_meas_counts_container
_pd_meas_counts_monitor
```

Counts measured at the measurement point as a funcof time, channel, tion angle, or some other variable (see _pd_meas_2theta_ ...) The defined fields are: _pd_meas_counts_total: scattering from the specimen (with background, specimen mounting or container scattering included); _pd_meas_counts_background: scattering measured without a specimen, specimen mounting, etc. often referred to as the instrument background; _pd_meas_counts_container: the specimen container or mounting without a specimen, includes background; _pd_meas_counts_monitor: counts measured by an incident beam monitor to calibrate the flux on the specimen.

Corrections for background, detector dead-time, etc., should not have been made to these values. Instead use _pd_proc_intensity_ for corrected diffractograms.

Note that counts-per-second values should be converted to total counts. If the counting time varies for different points, it may be included in the loop using _pd_meas_step_count_time.

E.s.d.'s may not be specified for these values as they will be the square-root of the number of counts. (If this is not true, the numbers are not counts and thus should be specified as _pd_meas_intensity_ values).

Appears in list. The permitted range is $0 \rightarrow \infty$. [pd_data]

_pd_meas_intensity_total

```
_pd_meas_intensity_background
```

_pd_meas_intensity_container

```
_pd_meas_intensity_monitor
```

Intensity measurements at the measurement point (see the defi-_pd_meas_2theta_). The defined fields nition of are: _pd_meas_intensity_total: scattering from the specimen (with background, specimen mounting or container scattering included); _pd_meas_intensity_background: scattering measured without а specimen, specimen mounting, etc. often referred to as the instrument background; _pd_meas_intensity_container: the specimen container or mounting without a specimen, includes background; _pd_meas_intensity_monitor : intensity measured by an incident beam monitor to calibrate the flux on the specimen.

Use these entries for measurements where intensity values are not counts (use _pd_meas_counts_ for event counting measurements where the estimated standard deviation is the square-root of the number of counts).

Corrections for background, detector dead-time, etc., should not have been made to these values. Instead use _pd_proc_intensity_ for corrected diffractograms.

_pd_meas_units_of_intensity should be used to specify the units of the intensity measurements. Appears in list.

[pd_data]

_pd_meas_units_of_intensity

(char)

(numb)

Units for intensity measurements when _pd_meas_intensity_ is used. Note that use of 'counts' or 'counts per second' here is to be strongly discouraged - convert the intensity measurements to counts and use _pd_meas_counts_ of and _pd_meas_step_count_time instead _pd_meas_intensity_

 $Example(s): \ \texttt{`estimated from strip chart'},$ 'arbitrary, from film density',

(numb)

'counts, with automatic deadtime correction applied' [pd_meas_method]

Code identifying the method for scanning reciprocal space. The designation 'fixed' should be used for measurements where film, a stationary position-sensitive or area detector or other nonmoving detection mechanism is used to measure diffraction intensities.

step	step scan
cont	continuous scan
tof	time of flight
disp	energy dispersive
fixed	stationary detection

[pd_meas_method]

(numb)

_pd_meas_2theta_scan

 2θ diffraction angle (in degrees) for intensity points measured in a scanning method. The scan method used (e.g. continuous or step scan) should be specified in item _pd_meas_scan_method. (white-beam) For fixed 20 experiments, use _pd_meas_2theta_fixed. In the case of continuous scan datasets, the 2θ value should be the value at the mid-point of the counting period. Associated with each _pd_meas_2theta_scan value will be _pd_meas_counts_ items. The 2θ values should not be corrected for non-linearity, zero offset, etc. Corrected values may be specified using _pd_proc_2theta_corrected.

Note that for datasets taken with constant step size, _pd_meas_2theta_range_(_min, _max, and _inc) may be used instead of _pd_meas_2theta_scan.

Appears in list. The permitted range is $-180.0 \rightarrow 360.0$. [pd_data]

_pd_meas_2theta_fixed (numb)

The	2θ	diffraction	angle	in	degrees	for
measu	rement	s in a white-bear	n fixed an	gle exp	eriment. For	mea-
sureme	ents wh	here 2θ is scanned	ed see _p	d_meas	_2theta_sc	an Of
_pd_m	eas_21	theta_range_*.				

The permitted range is $-180.0 \rightarrow 360.0$. [pd_meas_method]

_pd_meas_2theta_range_min	
_pd_meas_2theta_range_max	
_pd_meas_2theta_range_inc	(numb)

The range of 2θ diffraction angles in degrees for the measurement of intensities. These may be used in place of the _pd_meas_2theta_scan values for datasets measured with a constant step size.

The permitted range is $-180.0 \rightarrow 360.0$.	[pd_meas_method]
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_pd_meas_angle_chi _pd_meas_angle_omega _pd_meas_angle_phi _pd_meas_angle_2theta (numb)

The diffractometer angles in degrees for an instrument with an Euler circle. The definitions for these angles follow the convention of International Tables for X-ray Crystallography, Vol. 4, p 276.

May appear in list. The permitted range is $-180.0 \rightarrow 360.0$. [pd_data]

(char)

_pd_meas_detector_id

3

A code or number which identifies the measuring detector or channel number in a position sensitive, energy dispersive or other multiple detector instrument.

Calibration information, such as angle offsets, a calibration function to convert channel numbers to Q, energy, wavelength, angle, etc. should be described with _pd_calib_ values. If _pd_calib_conversion_eqn is used, the detector id's should be the number to be used in the equation.

Appears in list. Must match data name _pd_calib_detector_id. [pd_data]

_pd_meas_position

Appears in list.

(numb)

A linear distance in millimetres corresponding to the location where an intensity measurement is made. Used for detectors where a distance measurement is made as a direct observable - such as from a microdensitometer trace from film or a strip chart recorder. This is an alternative to _pd_meas_2theta_scan, which should only be used for instruments that record intensities directly against 2θ . For instruments where the position scale is non-linear, data item _pd_meas_detector_id should be used to record positions.

Calibration information, such as angle offsets or a function to convert this distance to a 2θ angle or *d*-space should be supplied with the _pd_calib_ values.

Do not confuse this with the instrument geometry descriptions given by _pd_instr_dist_.

[pd_data]

Measured time in microseconds for time-of-flight neutron measurements. Note that the flight distance may be specified using _pd_instr_dist_ * values.

Appears in list. The permitted range is $0 \rightarrow \infty$. [pd_data]

_pd_meas_step_count_time (numb)

The count time in seconds for each intensity measurement. If this value varies for different intensity measurements, then this item will be placed in the loop with the diffraction measurements. If a single fixed value is used, it may be recorded outside the loop. May appear in list. The permitted range is $0.0 \rightarrow \infty$. [pd_data]

_pd_meas_rocking	_axis	(char)
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Description of the axis (or axes) used to rotate or rock the specimen for better randomization of crystallites (see _pd_meas_rocking_angle).

chi omega phi May appear in list. [pd_meas_method]

pd_meas	_rocking_an	gle	(numb)
pu_meas	an	Яте	(num

The angular range in degrees a sample is rotated or oscillated during a measurement step (see _pd_meas_rocking_axis).

May appear in list. The permitted range is $0 \rightarrow 360.0$. [pd_data]

_pd_calib_[pd]

This section defines parameters used for calibration of the instrument used directly or indirectly in the interpretation of this dataset. The information in this section of the CIF should generally be written when the intensities are first measured, but from then on should remain unchanged. Loops may be used for calibration information that differs by detector channel.

Example 1

_pd_calib_std_external_id QuartzPlate|D500#1234-987|B. Toby|91-15-09|14:02 _pd_calib_std_external_name 'Arkansas Stone quartz plate'

_pd_calib_detector_id

(char)

A code which identifies the detector or channel number in a position sensitive, energy dispersive or other multiple detector instrument. Note that this code should match the code name used for _pd_meas_detector_id.

Appears in list as essential element of loop structure. May match subsidiary data name(s): _pd_meas_detector_id. [pd_instr]

_pd_calib_2theta_offset _pd_calib_2theta_off_point _pd_calib_2theta_off_min _pd_calib_2theta_off_max (numb)

 $_pd_calib_2theta_offset$ defines an offset angle (in degrees) used to calibrate 2θ (as defined in $_pd_meas_2theta_)$ Calibration is done by adding the offset:

 $2\theta_{calibrated} = 2\theta_{measured} + 2\theta_{offset}$

For cases where the $_pd_calib_2theta_offset$ value is not a constant, but rather varies with 2θ , a set of offset values can be supplied in a loop. In this case, the value where the offset has been determined can be specified as $_pd_calib_2theta_off_point$. Alternatively a range where the offset is applicable can be specified using $_pd_calib_2theta_off_min$ and $_pd_calib_2theta_off_max$.

May appear in list containing _pd_calib_detector_id. The permitted range is -180.0 [pd_instr]

_pd_calib_std_internal_name (char)

Identity of material(s) used as an internal intensity standard.

May appear in list containing _pd_calib_detector_id.

Example(s): 'NIST 640a Silicon standard', 'Al203'

[pd_instr]

(numb)

_pd_calib_std_internal_mass_%

Percent presence of the internal standard specified by the data item _pd_calib_std_internal_name expressed as 100 times the ratio of the amount of standard added to the original sample mass.

May appear in list containing $pd_calib_detector_id$. The permitted range is $0.0 \rightarrow 100.0$. [pd_instr]

_pd_calib_std_external_id _pd_calib_std_external_name (char) Identifies the dataset used as an external standard for the diffraction angle or the intensity calibrations. *_name specifies the name of the material and *_id the _pd_block_id for the CIF containing calibration measurements. If more than one dataset is used for calibration, these fields may be looped.

May appear in list containing _pd_calib_detector_id. [pd_instr]

_pd_calib_conversion_eqn

(char)

The calibration function to convert a channel number supplied in _pd_meas_detector_id for a position sensitive or energy dispersive detector or the distance supplied in _pd_meas_distance_value to Q, energy, angle... Use _pd_calib_std_external_* to define a pointer to the file or data block containing the information used to define this function.

[pd_instr]

_pd_calib_detector_response

(numb)

A value that indicates the relative sensitivity of each detector. This can compensate for differences in electronics, size and collimation. Usually, one detector or the mean for all detectors will be assigned the value of 1.

Appears in list containing <code>_pd_calib_detector_id</code>. The permitted range is $0.0 \rightarrow \infty$. [pd_instr]

_pd_calib_special_details

(char)

Descriptive information about how the instrument was calibrated, particularly for instruments where calibration information is used to make hardware settings that would otherwise be invisible once data collection is completed. Do not use this item to specify information that can be specified using other _pd_calib_* items.

[pd_instr]

_pd_spec_[pd]

This section contains information about the specimen used for measurement of the diffraction dataset. Note that information about the sample (the batch of material where the specimen was obtained), is specified in _pd_prep_.

Example 1

_pd_spec_mounting	2
_pd_spec_mount_mode	transmission
_pd_spec_orientation	horizontal
_pd_spec_preparation	?

_pd_spec_description

(char)

A description of the specimen such as the source of the specimen, identification of standards, mixtures, *etc.*

[pd_spec]

The size of the specimen in three mutually perpendicular directions in millimetres. The perpendicular to the plane containing the incident and scattered beam is the _axial direction. In transmission geometry, the scattering vector is parallel to *_equat and in reflection geometry the scattering vector is parallel to *_thick.

The permitted range is $0.0 \rightarrow \infty$. [pd_spec]

_pd_spec_mounting (char)

A description of how the specimen is mounted.

Example(s): 'vanadium can with He exchange gas',

'quartz capillary',

'packed powder	pellet', 'drifted powder	on off-cut Si',
'drifted powder	r on kapton film'	[pd_spec]

_pd_spec_mount_mode	(char)
A description code of beam path through the specimen.	
reflection	

reflection	
transmission	[pd_spec]

_pd_spec_orientation (char)

The orientation of the ω (θ) and 2θ axis. Note that this axis is parallel to the specimen axial axis and perpendicular to the plane containing the incident and scattered beams. Thus for a horizontal orientation, scattering measurements are made in a plane perpendicular to the ground (the 2θ axis is parallel to the ground); for vertical orientation scattering, measurements are made in a plane parallel with the ground (the 2θ axis is perpendicular to the ground). 'Both' is appropriate for experiments where measurements are made in both planes, for example using 2-D detectors.

horizontal	
vertical	
both	[pd_spec]

_pd_spec_preparation

A description of preparation steps for producing the diffraction specimen from the sample. Include any procedures related to grinding, sieving, spray drying, *etc.* For information relevant to how the sample is synthesized, use the _pd_prep_ entries.

Example(s): 'wet grinding in acetone',	
'sieved through 200 cm mesh',	
'spray dried in water with 1% clay'	[pd_spec]
, ,	<i>(</i> 1)
_pd_spec_shape	(char)
A description code of the specimen shape.	
cylinder	
flat_sheet	
irregular	[pd_spec]

Descriptive information about the specimen that cannot be included in other data items. [pd_spec]

_pd_instr_[pd]

This section contains information relevant to the instrument used for the diffraction measurement. For most laboratories, very little of this information will change, so a standard file may be prepared and included with each dataset.

Note that several definitions in the core CIF dictionary example, are relevant here. For use: _diffrn_radiation_wavelength for the source wavelength, _diffrn_radiation_type for the X-ray wavelength type, _diffrn_radiation_source for the radiation source, _diffrn_radiation_polaris_ratio for the source polarization. _diffrn_radiation_probe for the radiation type, For datasets measured with partially monochromatized radiation, for example, where both $K\alpha_1$ and $K\alpha_2$ are present, it is important that all wavelengths present be included using a loop_ for _diffrn_radiation_wavelength, possibly with _diffrn_radiation_wavelength_id and _diffrn_radiation_wavelength_wt. It may also be useful to create a "dummy" id to use for labeling peaks/reflections where the $K\alpha_1$ and $K\alpha_2$ wavelengths are not resolved. Set _diffrn_radiation_wavelength_wt to be 0 for such a dummv id.

In the _pd_instr_ definitions, the term monochromator refers to a primary beam (pre-specimen) monochromator and the term analyser refers to post-diffraction (postspecimen) monochromator. The analyser may be fixed for specific wavelength or may be capable of being scanned.

For multiple detector instruments it may be necessary to loop the *_anal/detc or *_samp/detc values (for _pd_instr_dist, _pd_instr_divg_, _pd_instr_slit_ and _pd_instr_soller) with the detector id's (_pd_calib_detector_id).

It is strongly recommended that the core dictionary term _diffrn_radiation_probe (specifying the nature of the radiation used) be employed for all datasets.

Example 1

(char)

_pd_instr_slit_eq_src/samp	1.
_pd_instr_slit_eq_anal/detc	0.2
_pd_instr_geometry _pd_instr_monochr_post_spec _pd_instr_cons_illum_flag	Bragg-Brentano 'graphite (0001)' no

_pd_instr_geometry

A description of the diffractometer type or geometry.

Example(s): 'Bragg-Brentano', 'Guinier', ; Parallel beam non-focussing optics with channel cut monochromator and linear position sensitive detector

[pd_instr]

(char)

_pd_instr_monochr_pre_spec _pd_instr_monochr_post_spec (char)

Indicates the method used to obtain monochromatic radiation. Use _pd_instr_monochr_pre_spec to describe the primary beam monochromator (pre-specimen monochromation). Use _pd_instr_monochr_post_spec to specify the post-diffraction analyzer (post-specimen) monochromation.

(numb)

When a monochromator crystal is used, the material and the indices of the Bragg reflection are specified.

Note that monochromators may have either 'parallel' or 'antiparallel' orientation. It is assumed that the geometry is parallel unless specified otherwise. In a parallel geometry, the position of the monochromator allows the incident beam and the final post-specimen and post-monochromator beam to be as close to parallel as possible. In a parallel geometry, the diffracting planes in the specimen and monochromator will be parallel when $2\theta_{monochromator}$ is equal to $2\theta_{specimen}$. For further discussion see R. Jenkins and R. Snyder, Introduction to X-ray Powder Diffraction, Wiley (1996) p164-5.

May appear in list.

Example(s): 'Zr filter',

'Ge 220', 'none', 'equatorial mounted graphite (0001)', 'Si (111), antiparallel' [pd_instr]

```
_pd_instr_2theta_monochr_pre
```

_pd_instr_2theta_monochr_post The 2θ angle for pre-specimen or post-specimen monochromator (see _pd_instr_monochr_pre_spec

_pd_instr_monochr_post_spec).

May appear in list. The permitted range is $-180.0 \rightarrow 180.0$. [pd_instr]

_pd_instr_location (char)

The name and location of the instrument where measurements were made. This is used primarily to identify datasets measured away from the author's home facility, at shared resources such as a reactor or spallation source.

Example(s): 'SEPD diffractometer, IPNS, Argonne National Lab (USA)' [pd instr]

_pd_instr_dist_src/mono	
_pd_instr_dist_mono/samp	
_pd_instr_dist_src/samp	
_pd_instr_dist_samp/anal	
_pd_instr_dist_anal/detc	
_pd_instr_dist_samp/detc	(numb)

Specifies distances in millimetres for the instrument geometry: _dist_src/mono, the distance from the radiation source to the monochromator, _dist_mono/samp, the distance from the monochromator to the specimen, _dist_src/samp, the distance from the radiation source to the specimen, _dist_samp/anal, the distance from the specimen to the analyser, _dist_anal/detc, the distance from the analyser to the detector, _dist_samp/detc, the distance from the specimen to the detector.

Note, _src/samp is used in place of _src/mono and _mono/samp, if there is no monochromator in use. Also, _samp/detc is used in place of _samp/anal and _anal/detc, if there is no analyser in use.

May appear in list. The permitted range is $0.0 \rightarrow \infty$. [pd_instr]

_pd_instr_divg_eq_src/mono _pd_instr_divg_eq_mono/samp _pd_instr_divg_eq_src/samp _pd_instr_divg_eq_samp/anal _pd_instr_divg_eq_anal/detc (numb)

_pd_instr_divg_eq_samp/detc

(numb)

Describes collimation in the equatorial plane (the plane containing the incident and diffracted beams) for the instrument. Values are the maximum divergence angles in degrees, as limited by slits or other beam-line optics other than Soller slits (see _pd_instr_soller_eq_). eq_src/mono, collimation between the radiation source and the monochromator, eq_mono/samp, collimation between the monochromator and the specimen, eq_src/samp, collimation between the radiation source and the specimen, eq_samp/anal, collimation between the specimen and the analyser, eq_anal/detc, collimation between the analyser and the detector, eq_samp/detc, collimation between the specimen and the detector.

Note, _src/samp is used in place of _src/mono and _mono/samp, if there is no monochromator in use and _samp/detc is used in place of _samp/anal and _anal/detc, if there is no analyser in use.

May appear in list. The permitted range is $0.0 \rightarrow \infty$. [pd_instr]

_pd_instr_divg_ax_src/mono	
_pd_instr_divg_ax_mono/samp	
_pd_instr_divg_ax_src/samp	
_pd_instr_divg_ax_samp/anal	
_pd_instr_divg_ax_anal/detc	
_pd_instr_divg_ax_samp/detc	(numb)

Describes collimation in the axial direction (perpendicular to the plane containing the incident and diffracted beams) for the instrument. Values are the maximum divergence angles in degrees, as limited by slits or other beam-line optics other than Soller slits (see _pd_instr_soller_ax_). ax_src/mono, collimation between the radiation source and the monochromator, ax_mono/samp, collimation between the monochromator and the specimen, ax_src/samp, collimation between the radiation source and the specimen, ax_samp/anal, collimation between the specimen and the analyser, ax_anal/detc, collimation between the analyser and the detector, ax_samp/detc, collimation between the specimen and the detector.

Note, _src/samp is used in place of _src/mono and _mono/samp, if there is no monochromator in use and _samp/detc is used in place of _samp/anal and _anal/detc, if there is no analyser in use.

May appear in list. The permitted range is $0.0 \rightarrow \infty$. [pd_instr]

_pd_instr_slit_eq_src/mono _pd_instr_slit_eq_mono/samp _pd_instr_slit_eq_src/samp _pd_instr_slit_eq_samp/anal _pd_instr_slit_eq_anal/detc _pd_instr_slit_eq_samp/detc (numb)

Describes collimation in the equatorial plane (the plane containing the incident and diffracted beams) for the instrument as a slit width (as opposed to a divergence angle.) Values are the width of the slit (in millimetres) defining: eq_src/mono, collimation between the radiation source and the monochromator, eq_mono/samp, collimation between the monochromator and the specimen, eq_src/samp, collimation between the radiation source and the specimen, eq_samp/anal, collimation between the specimen and the analyser, eq_anal/detc, collimation between the analyser and the detector, eq_samp/detc, collimation between the specimen and the detector.

Note, _src/samp is used in place of _src/mono and _mono/samp, if there is no monochromator in use and _samp/detc is used in place of _samp/anal and _anal/detc, if there is no analyser in use.

May appear in list. The permitted range is $0.0 \rightarrow \infty$. [pd_instr]

```
_pd_instr_slit_ax_src/mono
_pd_instr_slit_ax_mono/samp
_pd_instr_slit_ax_src/samp
_pd_instr_slit_ax_samp/anal
_pd_instr_slit_ax_anal/detc
_pd_instr_slit_ax_samp/detc
```

Describes collimation in the axial direction (perpendicular to the plane containing the incident and diffracted beams) for the instrument as a slit width (as opposed to a divergence angle.) Values are the width of the slit (in millimetres) defining: ax_src/mono, collimation between the radiation source and the monochromator, ax_mono/samp, collimation between the monochromator and the specimen, ax_src/samp, collimation between the radiation source and the specimen, ax_samp/anal, collimation between the specimen and the analyser, ax_anal/detc, collimation between the specimen and the detector, ax_samp/detc, collimation between the specimen and the detector.

Note, _src/samp is used in place of _src/mono and _mono/samp, if there is no monochromator in use and _samp/detc is used in place of _samp/anal and _anal/detc, if there is no analyser in use.

May appear in list. The permitted range is $0.0 \rightarrow \infty$. [pd_instr]

_pd_instr_soller_eq_src/mono	
_pd_instr_soller_eq_mono/samp	
_pd_instr_soller_eq_src/samp	
_pd_instr_soller_eq_samp/anal	
_pd_instr_soller_eq_anal/detc	
_pd_instr_soller_eq_samp/detc	

Describes collimation in the equatorial plane (the plane containing the incident and diffracted beams) for the instrument. Values are the maximum divergence angles in degrees, as limited by Soller slits located between: eq_src/mono, collimation between the radiation source and the monochromator, eq_mono/samp, collimation between the monochromator and the specimen, eq_src/samp, collimation between the radiation source and the specimen, eq_samp/anal, collimation between the specimen and the analyser, eq_anal/detc, collimation between the specimen and the detector, eq_samp/detc, collimation between the specimen and the detector.

Note, _src/samp is used in place of _src/mono and _mono/samp, if there is no monochromator in use and _samp/detc is used in place of _samp/anal and _anal/detc, if there is no analyser in use.

May appear in list. The permitted range is $0.0 \rightarrow \infty$. [pd_instr]

pd	_instr_	_soller_	_ax_	_src/r	nono
pd	_instr_	soller	ax	_mono/	/samp
	÷ +				

_pd_instr_soller_ax_src/samp

_pd_instr_soller_ax_samp/anal

_pd_instr_soller_ax_anal/detc

_pd_instr_soller_ax_samp/detc

Describes collimation in the axial direction (perpendicular to the plane containing the incident and diffracted beams) for the instrument. Values are the maximum divergence angles in degrees, as limited by Soller slits located between: ax_src/mono, collimation between the radiation source and the monochromator, ax_mono/samp, collimation between the monochromator and the specimen, ax_src/samp, collimation between the radiation source and the specimen, ax_samp/anal, collimation between the specimen and the analyser, ax_anal/detc, collimation between the analyser and the detector, ax_samp/detc, collimation between the specimen and the detector.

Note, _src/samp is used in place of _src/mono and _mono/samp, if there is no monochromator in use and _samp/detc is used in place of _samp/anal and _anal/detc, if there is no analyser in use.

May appear in list. The permitted range is $0.0 \rightarrow \infty$. [pd_instr]

_pd_instr_source_size_ax

_pd_instr_source_size_eq

_pd_instr_cons_illum_flag

Axial and equatorial intrinsic dimensions of the radiation source (in millimetres). The perpendicular to the plane containing the incident and scattered beam is the axial $(_ax)$ direction.

The permitted range is $0.0 \rightarrow \infty$. [pd_instr]

(numb)

Use 'yes' for instruments where the divergence slit is thetacompensated to yield a constant illumination length (also see '_pd_instr_cons_illum_len').

For other flat-plate instruments, where the illumination length changes with 2θ , specify 'no'. Note that if the length is known, it may be specified using '_pd_instr_var_illum_len'.

yes no

7

(numb)

(numb)

(numb)

[pd_instr]

_pd_instr_cons_illum_len (numb) Length of the specimen that is illuminated by the radiation source (in millimetres).

Use _pd_instr_cons_illum_len for instruments where the illumination length does not vary with 2θ , by adjustment of the divergence slits (sometimes known as θ -compensated slits). Use _pd_instr_cons_illum_len for instruments where the divergence slit is fixed so that the illumination length varies with 2θ when the length is known.

The permitted range is $0.0 \rightarrow \infty$. [pd_instr]

_pd_instr_var_illum_len

(numb)

Length of the specimen that is illuminated by the radiation source (in millimetres) for instruments where the illumination length varies with 2θ (fixed divergence slits). The _pd_instr_var_illum_len values should be included in the same loop as the intensity measurements (_pd_meas_).

See _pd_instr_cons_illum_len for instruments where the divergence slit is θ -compensated to yield a constant illumination length.

Appears in list. The permitted range is $0.0 \rightarrow \infty$. [pd_data]

_pd_instr_beam_size_ax _pd_instr_beam_size_eq

(numb)

Axial and equatorial dimensions of the radiation beam at the specimen position (in millimetres). The perpendicular to the plane containing the incident and scattered beam is the axial $(_ax]$ direction.

The permitted range is $0.0 \rightarrow \infty$.

_pd_instr_special_details (char)

A brief description of the instrument giving details that cannot be given in other _pd_instr_ entries.

[pd_instr]

[pd_data]

_pd_proc_[pd]

This section contains the diffraction dataset after processing and application of correction terms. If the dataset is reprocessed, this section may be replaced (with addition of a new _pd_block_id entry).

_pd_proc_info_author_address

The address of the person or persons who processed the data. If there is more than one person this may be looped with _pd_proc_info_author_name.

May appear in list containing _pd_proc_info_author_name. [pd_proc_info]

_pd_proc_info_author_email (char)

The email address of the person or persons who processed the data. If there is more than one person this will be looped with _pd_proc_info_author_name.

May appear in list containing _pd_proc_info_author_name. [pd_proc_info]

_pd_proc_info_author_fax (char)

The fax number of the person or persons who processed the data. If there is more than one person this may be looped with _pd_proc_info_author_name.

May appear in list containing _pd_proc_info_author_name. [pd_proc_info]

The name of the person or persons who processed the data, if different from the person(s) who measured the dataset. The family name(s), followed by a comma, precedes the first names or initials. For more than one person use a loop to specify multiple values.

May appear in list. [pd_proc_info]

_pd_proc_info_author_phone (char)

The telephone number of the person or persons who processed the data. If there is more than one person this may be looped with _pd_proc_info_author_name.

May appear in list containing _pd_proc_info_author_name. [pd_proc_info]

_pd_proc_info_datetime (char)

Date(s) and time(s) when the dataset was processed. May be looped if multiple processing steps were used.

Dates and times should be specified in the standard CIF format '*yyyy-mm-ddThh:mm:ss+zz*'. Use of seconds and a time zone is optional, but use of hours and minutes is strongly encouraged.

May appear in list.

Example(s): '1990-07-13T14:40' [pd_proc_info]

_pd_proc_info_excluded_regions

(char)

Description of regions in the diffractogram excluded from processing along with a justification of why the datapoints were not used.

Example(s):

'20 to 21 degrees unreliable due to beam dump' [pd_proc_info]

_pd_proc_info_data_reduction (char)

Description of processing steps applied in the data reduction process (background subtraction, α -2 stripping, smoothing, *etc.*). Include details of the program(s) used, *etc.*

[pd_proc_info]

(char)

(numb)

_pd_proc_info_special_details

Detailed description of any non-routine processing steps applied due to any irregularities in this particular dataset.

[pd_proc_info]

_pd_proc_number_of_points (numb) The total number of data points in the processed diffractogram.

The permitted range is $1 \rightarrow \infty$. [pd_proc_data]

_pd_proc_intensity_net	
_pd_proc_intensity_total	
_pd_proc_intensity_calc_bkg	
_pd_proc_intensity_fix_bkg	
_pd_proc_intensity_incident	
_pd_proc_intensity_norm	

_pd_proc_intensity_net contains intensity values for the processed diffractogram for each data point (see _pd_proc_2theta_, _pd_proc_wavelength, *etc.*) after correction and normalization factors have been applied (in contrast to _pd_meas_counts_ values which are uncorrected). _pd_proc_intensity_total contains intensity values for the processed diffractogram for each data point where background, normalization and other corrections have not been applied.

Inclusion of e.s.d.'s for these values is strongly recommended.

_pd_proc_intensity_calc_bkg is intended to contain the background intensity for every data point where the background function has been fit or estimated (for example in all Rietveld and profile fits).

If the background is estimated for a limited number of points and the calculated background is then extrapolated from these fixed points, indicate the background values for these points with_pd_proc_intensity_fix_bkg. Use a value of '?' for data points where a fixed background has not been defined. The extrapolated background at every point may be specified using _pd_proc_intensity_calc_bkg.

8

(char)

Background values should be on the same scale as the _pd_proc_intensity_net values. Thus normalization and correction factors should be applied before background subtraction (or should be applied to the background values equally).

If the intensities have been corrected for a variation of the incident intensity as a function of a data collection variable (examples: source fluctuations in synchrotrons, θ -compensated slits in conventional diffractometers, spectral corrections for whitebeam experiments) the correction function should be specified as _pd_proc_intensity_incident. The normalization should be specified in _pd_proc_intensity_incident as a value to be used to divide the measured intensities to obtained the normalized diffractogram. Thus, the _pd_proc_intensity_incident values should increase as the incident flux is increased.

The other normalization factors applied to the dataset (for example, Lp corrections, compensation for variation in counting time) may be specified in _pd_proc_intensity_norm. The function should be specified as the one used to divide the measured intensities.

Appears in list. The permitted range is $0.0 \rightarrow \infty$. [pd_data]

_pd_proc_2theta_corrected

(numb)

(numb)

The 2θ diffraction angle in degrees of an intensity measurement where 2θ is not constant. Used if corrections such as for non-linearity, zero offset, *etc.*, have been applied to the _pd_meas_2theta_ values or if 2θ values are computed. If the 2θ values are evenly spaced, _pd_proc_2theta_range_min, _pd_proc_2theta_range_max and _pd_proc_2theta_range_inc may be used to specify the 2θ values.

Appears in list. The permitted range is $-180.0 \rightarrow 180.0$. [pd_data]

```
_pd_proc_2theta_range_min
_pd_proc_2theta_range_max
_pd_proc_2theta_range_inc (numb)
```

The range of 2θ diffraction angles in degrees for the measurement of intensities. These may be used in place of the _pd_proc_2theta_corrected values; or in the case of white beam experiments it will define the fixed 2θ value.

The permitted range is $-180.0 \rightarrow 180.0$. [pd_data]

_pd_proc_energy_incident _pd_proc_energy_detection (numb)

Incident energy in electron-volts of the source computed from secondary calibration information (time-of-flight and synchrotron). Detection energy in electron-volts selected by the analyser, if not the same as the incident energy (triple-axis or energy dispersive data). This may be a single value or may vary for each data point (triple-axis and time-of-flight data).

May appear in list. The permitted range is $0.0 \rightarrow \infty$. [pd_data]

_pd_proc_wavelength

Wavelength in ångströms for the incident radiation as computed from secondary calibration information. This will be most appropriate for time-of-flight and synchrotron measurements. This will be a single value for CW methods or may vary for each data point and be looped with the intensity values for energydispersive measurements.

May appear in list. The permitted range is $0.0 \rightarrow \infty$. [pd_data]

_pd_proc_d_spacing (numb)

d-spacing corresponding to an intensity point from Bragg's law, $d = \lambda/(2 \sin \theta)$ in units of ångströms.

Appears in list. The permitted range is $0.0 \rightarrow \infty$. [pd_data]

_pd_proc_recip_len_Q (numb)

Length in reciprocal space $(|Q| = 2\pi/d)$ corresponding to an intensity point. Units are inverse ångströms.

Appears in list. The permitted range is $0.0 \rightarrow \infty$. [pd_data]

_pd_proc_ls_[pd]

This section is used to define parameters relevant to a leastsquares fit to a powder diffractogram, using a Rietveld or other full-profile (*e.g.* Pauley or Le-Bail methods) fit.

Note that values in this section refer to full-pattern fitting. Use the appropriate items for single-crystal analyses from the core dictionary for structural refinements using diffraction intensities estimated from a powder diffractogram by pattern decomposition methods. Also note that many entries in the core _refine_ls_* entries may also be useful (for example _refine_ls_shift/esd_*).

_pd_proc_ls_weight

(numb)

(numb)

Weight applied to each profile point. These values may be omitted if the weights are $1/\sigma^2$ where σ is the e.s.d. for the _pd_proc_intensity_net values.

A weight value of zero is used to indicate a data point not used for refinement (see $_pd_proc_info_excluded_regions$). Appears in list. The permitted range is $0 \rightarrow \infty$. [pd_data]

_pd_proc_ls_prof_R_factor _pd_proc_ls_prof_wR_factor _pd_proc_ls_prof_wR_expected

Rietveld/Profile fit *R*-factors.

Note that the *R*-factor computed for Rietveld refinements using the extracted reflection intensity values (often called the Rietveld or Bragg *R*-factor, R_b) is not properly a profile *R*-factor. This *R*-factor may be specified using _refine_ls_R_I_factor (Some authors report _refine_ls_R_Fsqd_factor or _refine_ls_R_factor_all as the Rietveld or Bragg *R*-factor. While it is appropriate to compute and report any or all of these *R*-factors, the names "Rietveld or Bragg *R*-factor" refer to _refine_ls_R_I_factor).

 $_pd_proc_ls_prof_R_factor$, often called R_p , is an unweighted fitness metric for the agreement between the observed and computed diffraction patterns

$$R_p = \sum_i |I_{obs}(i) - I_{calc}(i)| / \sum_i (I_{obs}(i))$$

_pd_proc_ls_prof_wR_factor, often called R_{wp} , is a weighted fitness metric for the agreement between the observed and computed diffraction patterns

$$R_{wp} = \sqrt{\left\{\sum_{i} (w(i) * [I_{obs}(i) - I_{calc}(i)]^2) / \sum_{i} (w(i) * [I_{obs}(i)]^2)\right\}}$$

_pd_proc_ls_prof_wR_expected, sometimes called the theoretical R_{wp} or R_e , is a weighted fitness metric for the statistical precision of the dataset. For an idealized fit, where all deviations between the observed intensities and those computed from the model are due to statistical fluctuations, the observed R_{wp} should match the expected *R*-factor. In reality R_{wp} will always be higher than R_e .

$$R_{e} = \sqrt{\{(n-p)/\sum_{i} (w(i) * [I_{obs}(i)]^{2})\}}$$

Note that in the above equations,

w(i) is the weight for the *i*th data point (see _pd_proc_ls_weight)

 $I_{obs}(i)$ is the observed intensity for the *i*th data point, sometimes referred to as y_i(obs) or y_{oi}. (See _pd_meas_count_total, _pd_meas_intensity_total Of _pd_proc_total).

 $I_{calc}(i)$ is the computed intensity for the *i*th data point with background and other corrections applied to match the scale of the observed dataset, sometimes referred to as $y_i(calc)$ or y_{ci} . (See _pd_calc_intensity_total).

n is the total number of data points (see

The permitted range is $0.0 \rightarrow \infty$.

_pd_proc_number_of_points) less the number of data points excluded from the refinement.

p is the total number of refined parameters.

[pd_proc_ls]

Description of the background treatment mechanism use the dataset.

For refinements where background is computed from a function fit to the difference between obs - calc, it is recommended that in addition to a description of the function (e.g. Chebychev polynomial), the actual equation(s) used be included in T_EX, or a programming language such as FORTRAN or C. Include also the values used for the coefficients used in the background function with their e.s.d.'s. The background values for each data point computed from the function should be specified in _pd_proc_intensity_calc_bkg.

If background correction is performed using extrapolation from a set of points at fixed locations, these points should be defined using _pd_proc_intensity_fix_bkg, and _pd_proc_ls_background_function should indicate the extrapolation method (linear extrapolation, spline, etc.). _pd_proc_ls_background_function should also indicate how the points were determined (automatically, by visual estimation, etc.) and whether the values were refined to improve the agreement. The extrapolated background intensity value for each data point should be specified in _pd_proc_intensity_calc_bkg.

[pd_proc_ls]

Description of the preferred orientation correction if such a correction is used. Omitting this entry implies no preferred orientation correction has been used. If a function form is used, it is recommended that the actual equation in TEX, or a programming language, be used to specify the function as well as a description. Include the value(s) used for the correction with e.s.d.'s.

[pd_proc_ls]

(char)

_pd_proc_ls_profile_function

10

_pd_calc_intensity_net _pd_calc_intensity_total

Intensity values for a computed diffractogram at each angle

setting. Values should be computed at the same locations as the processed diffractogram, and thus the numbers of points will be defined by _pd_proc_number_of_points and point positions may be defined using _pd_proc_2theta_range_ or _pd_proc_2theta_corrected.

Use _pd_calc_intensity_net if the computed diffractogram does not contain background or normalization corrections and thus is specified on the same scale as the _pd_proc_intensity_net.

Use _pd_calc_intensity_total if the computed diffraction pattern includes background or normalization corrections (or both) and thus is specified on the same scale as the observed intensities (_pd_meas_counts_ Or _pd_meas_intensity_).

If an observed pattern is included, _pd_calc_intensity_ should be looped with either _pd_proc_intensity_net, _pd_meas_counts_Of _pd_meas_intensity_)

Appears in list. The permitted range is $0.0 \rightarrow \infty$. [pd_data]

_pd_calc_method

A description of the method used for calculation of the intensities in _pd_calc_intensity. If the pattern was calculated from crystal structure data, the atom coordinates and other crystallographic information should be included using the CIF core _atom_site_ and _cell_ data items.

Description of the profile function used to fit the dataset. If a function form is used, it is recommended that the actual equation in T_FX, or a programming language, be used to specify the function as well as a description. Include the values used for the profile function coefficients and their e.s.d.'s.

Describes where peak intensity computation is discontinued as

a fraction of the intensity of the peak at maximum. Thus for a

value of 0.005, the tails of a diffraction peak are neglected after

the intensity has dropped below 0.5% of the diffraction intensity

[pd_proc_ls]

(numb)

(char)

(numb)

(char)

[pd_proc_ls]

_pd_proc_ls_peak_cutoff

at the maximum.

Additional characterization information relevant to non-routine steps used for refinement of a structural model that cannot be specified elsewhere.

[pd_proc_ls]

_pd_calc_[pd]

This section is used for storing a computed diffractogram This may be a simulated powder pattern for a material program such as LAZY/PULVERIX or the computed intensities from a Rietveld refinement.

This section contains peak information extracted from the measured or, if present, the processed diffractogram. Each peak in this table will have a unique label (see _pd_peak_id). The reflections and phases associated with each peak will be specified in a later section (see the _pd_refln_ and _pd_phase_ sections).

Note that peak positions are customarily determined from the processed diffractogram and thus corrections for position and intensity will have been previously applied.

_pd_peak_id

(char)

An arbitrary code is assigned to each peak. Used to link with _pd_refln_peak_id so that multiple *hkl* and/or phase identifications can be assigned to a single peak. Each peak will have a unique code. In cases where two peaks are severely overlapped, it may be desirable to list them as a single peak.

A peak id must be included for every peak.

Appears in list as essential element of loop structure. Uniqueness of loop packet tested on _pd_peak_id. May match subsidiary data name(s): _pd_refln_peak_id. [pd_peak]

_pd_peak_intensity

(numb)

Integrated area for the peak, with the same scaling as the <u>_pd_proc_intensity</u>* values. Good practice is to include e.s.d.'s for these values.

Appears in list containing $_pd_peak_id$. The permitted range is $0.0 \rightarrow \infty$. [pd_peak]

_pd_peak_pk_height

(numb)

(numb)

The maximum intensity of the peak, either extrapolated, or the highest observed intensity value. The same scaling is used for the _pd_proc_intensity_ values. Good practice is to include e.s.d.'s for these values.

Appears in list containing pd_peak_id . The permitted range is $0.0 \rightarrow \infty$. [pd_peak]

_pd_peak_2theta_centroid _pd_peak_2theta_maximum

Position of the centroid and maximum of a peak as a 2θ angle in degrees.

Appears in list containing $_{pd_peak_id}$. The permitted range is $0.0 \rightarrow 180.0$. [pd_peak]

_pd_peak_d_spacing (numb)

Peak position as a d-spacing in ångströms.

Appears in list containing pd_{peak} id. The permitted range is $0.0 \rightarrow \infty$. [pd_peak]

_pd_peak_width_d_spacing (numb)

Peak width as full-width at half-maximum expressed as a *d*-spacing in ångströms.

_pd_peak_width_2theta

(numi	5)

(char)

(char)

Peak width as full-width at half-maximum expressed as 2θ value in degrees.

Appears in list containing pd_peak_id . The permitted range is $0.0 \rightarrow 180.0$. [pd_peak]

_pd_peak_wavelength_id

Code identifying the wavelength appropriate for this peak from the wavelengths in the _diffrn_radiation_ list. (See _diffrn_radiation_wavelength_id.) Most commonly used to distinguish $K\alpha_1$ peaks from $K\alpha_2$ or designate where $K\alpha_1$ and $K\alpha_2$ peaks cannot be resolved. For complex peak tables, with multiple superimposed peaks, specify wavelengths in the reflection table using _pd_refln_wavelength_id rather than identifying peaks by wavelength.

Appears in list containing _pd_peak_id. Must match data name _diffrn_radiation_wavelength_id. [pd_peak]

_pd_peak_special_details

Detailed description of any non-routine processing steps used for peak determination or other comments related to the peak table that cannot be described elsewhere.

[pd_peak_method]

_pd_phase_[pd]

This section contains a description of the crystalline phases present in the powder diffraction dataset. Note that if multiple phase Rietveld or other structural analysis is performed, the structural results will be placed in different data blocks, using CIF entries from the core CIF dictionary.

The _pd_phase_block_id entry points to the CIF block with structural parameters for each crystalline phase. The _pd_phase_id serves to link to _pd_refln_phase_id which is used to label peaks by phase.

(char)

A block id code identifying the phase contributing to the diffraction peak. The data block containing the crystallographic information for this phase will be identified with a $_{pd_block_id}$ code matching the code in $_{pd_phase_block_id}$.

Appears in list containing	_pd_phase_id.	[pd_phase]
----------------------------	---------------	------------

pd_phase_name	(char)
---------------	--------

The name of the crystal phase identified by _pd_phase_id. It may be designated as unknown or by a structure type, *etc*.

May appear in list containing _pd_phase_id. [pd_phase]

/ 1		
(ch	lar)

A code for each crystal phase used to link with _pd_refln_phase_id.

Appears in list as essential element of loop structure. Uniqueness of loop packet tested on _pd_phase_id. May match subsidiary data name(s): _pd_refln_phase_id. [pd_phase]

r	ьd	pha	92	mag	29	7
_ ト	Ju_	pna	.o c _	ւաստ	_ a c	/0

_pd_phase_id

_pd_phase_block_id

(numb)

(*ch*

Percent composition of the specified crystal phase expressed as the total mass of the component with respect to the total mass of the specimen.

Appears in list containing _pd_phase_id. The permitted range is 0.0→100.0. [pd_phase]

_pd_refln_[pd]

This section provides a mechanism to identify each peak in the peak-table section $(_pd_peak_)$ with the phase(s) $(_pd_phase_id)$ and the reflection indices $(_refln_index_)$ associated with the peak. There are no restrictions on the number of phases or reflections associated with an observed peak. Reflections may also be included that are not observed; use "?" for the _pd_refln_peak_id.

_pd_refln_peak_id

(char)

Code which identifies the powder diffraction peak that contains the current reflection. This code must match a $_{pd_peak_id}$ code.

Appears in list containing _refln_index_h,_refln_index_k, _refln_index_1. Uniqueness of loop packet tested on_pd_refln_peak_id,_pd_refln_phase_id. Must match data name_pd_peak_id. [pd_refln]

_pd_refln_phase_id (char)

Code which identifies the crystal phase associated with this reflection. This code must match a _pd_phase_id code.

Appears in list containing _refln_index_h,_refln_index_k, _refln_index_1. Must match data name _pd_phase_id. [pd_refln]

_pd_refln_wavelength_id (char) Code which identifies the wavelength associated with the reflection and the peak pointed to by _pd_refln_peak_id. This code must match a _diffrn_radiation_wavelength_id code.

Appears in list containing _refln_index_h, _refln_index_k,_refln_index_l. Must match data name _diffrn_radiation_wavelength_id. [pd_refln]

_pd_prep_[pd]							
This section contains descriptive information on how the							
sample is prepared.							

_pd_prep_temperature

(numb)

(numb)

Preparation temperature of sample. This is particularly important for materials which are metastable at the measurement temperature, _diffrn_ambient_temperature.

The permitted range is $0.0 \rightarrow \infty$. [pd_prep]

_pd_prep_pressure

Preparation pressure of the sample in kilopascals. This is particularly important for materials which are metastable at the measurement pressure, _diffrn_ambient_pressure.

The permitted range is $0.0 \rightarrow \infty$. [pd_prep]

(numb)

_pd_prep_cool_rate

Cooling rate in Kelvins per minute for samples prepared at high temperatures. If the cooling rate is not linear or is unknown (*e.g.* quenched samples), it should be described instead in $_pd_prep_conditions$.

The permitted range is $0.0 \rightarrow \infty$. [pd_prep]

_pd_prep_conditions

(char)

A description of the how the material was prepared (reaction conditions, *etc.*)

[pd_prep]

_pd_char_[pd]

This section contains experimental (non-diffraction) information relevant to the chemical and physical nature of the material.

_pd_char_particle_morphology

(char)

A description of the sample morphology and estimates for particle sizes (before grinding/sieving, if noted by _pd_spec_preparation). Include the method used for these estimates (SEM, visual estimate...).

[pd_char]

(char)

(numb)

_pd_char_colour

The colour of the material used for the measurement. To facilitate more standardized use of names, the following guidelines for colour naming developed by Peter Bayliss for the ICDD should be used. Note that combinations of descriptors are separated by an underscore.

Allowed colours are: colourless, white, black, gray, brown, red, pink, orange, yellow, green, blue, violet

Colours may be modified using prefixes of: light, dark, whitish, blackish, grayish, brownish, reddish, pinkish, orangish, yellowish, greenish, bluish

Intermediate hues may be indicated with two colours: *e.g.* blue_green or bluish_green

For metallic materials, the term metallic may be added: *e.g.* reddish_orange_metallic for copper

The ICDD standard allows commas to be used for minerals that occur with ranges of colours; however this usage is not appropriate for description of a single sample.

Example(s): 'dark_green', 'orange_red', 'brownish_red', 'yellow_metallic' [pd_char]

_pd_char_atten_coef_mu_obs _pd_char_atten_coef_mu_calc

The observed and calculated linear attenuation coefficient, μ in units of inverse millimetres. Note that this quantity is sometimes referred to as the mass absorption coefficient, however, this term accounts for other potentially significant losses of incident radiation, for example incoherent scattering of neutrons.

The calculated μ will be obtained from atomic content of the cell, the average density (allowing for specimen packing) and the radiation wavelength. The observed μ will be determined by a transmission measurement. Note that _pd_char_atten_coef_mu_calc will differ from _exptl_absorpt_coefficient_mu if the packing density is not unity.

The permitted range is $0.0 \rightarrow \infty$. [pd_char]

Additional characterization information relevant to the sample or documentation of non-routine processing steps used for characterization.

[pd_char]